

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination WANG, ZHONGZE	
		Examiner Jennifer M. Kennedy	Art Unit 2812	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,313,014 B1	11-2001	Sakaguchi et al.	438/475
	B	US-6,350,703 B1	02-2002	Sakaguchi et al.	438/766
	C	US-2002/0070454 A1	06-2002	Yasukawa, Masahiro	257/760
	D	US-6,661,065 B2	12-2003	Kunikiyo, Tatsuya	257/411
	E	US-5,453,394 A	09-1995	Yonehara et al.	438/455
	F	US-5,405,802 A	04-1995	Yamagata et al.	438/459
	G	US-6,037,634 A	03-2000	Akiyama, Hajime	257/347
	H	US-5,841,171 A	11-1998	Iwamatsu et al.	257/347
	I	US-5,910,672 A	06-1999	Iwamatsu et al.	257/347
	J	US-2003/0085424	05-2003	Bryant et al.	257/347
	K	US-5,670,411	09-1997	Yonehara et al.	438/459
	L	US-2001/0020722	09-2001	Yang, Chien-Kuo	257/347
	M	US			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.